

ULTRAGrade™ Solution
Silicon ICP / ICP-MS Standard
10000 µg/mL

Catalog Number: ICP-114
Lot Number: CM-3551
Lot Issue Date: 07/02/2015
Expiration Date: 08/31/2022

Starting Material: ammonium hexafluorosilicate
 Starting Material Purity: 99.999%
 Starting Material Lot #: RM09360
 Matrix: 2% nitric acid and trace hydrofluoric acid in low TOC water (< 50 ppb)
 Atomic Weight Si: 28.09

Certified Value: 10007 ± 20 µg/mL

This analytical Reference Material (RM) was manufactured and verified in accordance with ULTRA's ISO 9001 registered quality system. The analyte concentration(s) were prepared and verified by an ISO Guide 34 / ISO 17025 accredited laboratory, and compared to calibration standards independently prepared using NIST SRM(s). The certified value and uncertainty value at the 95% confidence level for each analyte is determined gravimetrically.

Classical Wet Assay Method: Theoretical, based on gravimetric measurements

Confirmation by Inductively Coupled Plasma Spectroscopy (ICP / ICP/MS) vs. NIST SRM 3150

ULTRA uses purified acids, 18 megohm-cm double deionized water, calibrated Class A glassware & meticulously cleaned bottles in the manufacturing of ULTRAGrade standards. Balances used in the manufacturing of this standard are calibrated with weights traceable to NIST in compliance with ANSI/NCCL Z-540-1 and ISO 9001.

Trace Metallic Impurities in Solution Standard in µg/mL:

* Al <0.005 D	* Ga <0.005 ND	n Nb	n S
* Sb <0.005 ND	n Ge	n Os	n Ta
* As <0.005 ND	n Au	* Pd <0.005 ND	n Te
* Ba <0.005 ND	n Hf	* P <0.005 ND	n Tb
* Be <0.005 ND	n Ho	* Pt <0.005 ND	* Tl <0.005 ND
* Bi <0.005 ND	* In <0.005 ND	* K <0.005 ND	n Th
* B <0.005 ND	n Ir	n Pr	n Tm
* Cd <0.005 ND	* Fe <0.005 ND	n Re	* Sn <0.005 ND
* Ca <0.005 D	* La <0.005 ND	n Rh	* Ti <0.005 D
n Ce	* Pb <0.005 ND	n Rb	n W
n Cs	* Li <0.005 ND	n Ru	n U
* Cr <0.005 ND	n Lu	n Sm	* V <0.005 ND
* Co <0.005 ND	* Mg <0.005 ND	n Sc	n Yb
* Cu <0.005 ND	* Mn <0.005 ND	* Se <0.005 ND	n Y
n Dy	* Hg <0.005 ND	s Si	* Zn <0.005 ND
* Er <0.005 ND	* Mo <0.005 ND	* Ag <0.005 ND	n Zr
* Eu <0.005 ND	n Nd	* Na <0.005 ND	
* Gd <0.005 ND	* Ni <0.005 ND	* Sr <0.005 ND	

* - element checked for
 ND - not detected

I - spectral interference
 D - detected

n - not checked for
 s - solution standard element

Density of Solution (measured at 20.00°C ± 0.05°C): 1.0463 g/mL



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ISO 9001:2000
 Registered
 TUV USA, Inc.
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 William J. Leary
 Quality Assurance Manager